

# Serial Port Profile (SPP)

## **Bluetooth® Test Suite**

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# Contents

|          |                                                                                  |           |
|----------|----------------------------------------------------------------------------------|-----------|
| <b>1</b> | <b>Scope</b>                                                                     | <b>4</b>  |
| <b>2</b> | <b>References, definitions, and abbreviations</b>                                | <b>5</b>  |
| 2.1      | References                                                                       | 5         |
| 2.2      | Definitions                                                                      | 5         |
| 2.3      | Acronyms and abbreviations                                                       | 5         |
| <b>3</b> | <b>Test Suite Structure (TSS)</b>                                                | <b>6</b>  |
| 3.1      | Overview                                                                         | 6         |
| 3.2      | Test Strategy                                                                    | 6         |
| 3.3      | Test groups                                                                      | 7         |
| 3.3.1    | Generic SDP Integrated Tests                                                     | 7         |
| 3.3.2    | Application                                                                      | 7         |
| <b>4</b> | <b>Test cases (TC)</b>                                                           | <b>8</b>  |
| 4.1      | Introduction                                                                     | 8         |
| 4.1.1    | Test case identification conventions                                             | 8         |
| 4.1.2    | Conformance                                                                      | 8         |
| 4.1.3    | General Assumptions                                                              | 9         |
| 4.1.4    | Pass/Fail verdict conventions                                                    | 9         |
| 4.2      | Generic SDP Integrated Tests                                                     | 10        |
| 4.2.1    | Server Generic SDP Integrated Tests                                              | 10        |
| 4.2.1.1  | Serial Port Profile – Device B                                                   | 10        |
|          | SPP/DEVB/SGSIT/SERR/BV-01-C [Service record GSIT – SPP DevB]                     | 10        |
|          | SPP/DEVB/SGSIT/ATTR/BV-01-C [Attribute GSIT – Protocol Descriptor List]          | 10        |
|          | SPP/DEVB/SGSIT/ATTR/BV-02-C [Attribute GSIT – Bluetooth Profile Descriptor List] | 10        |
| 4.2.1.2  | Serial Port Profile – Attribute ID Offset String tests                           | 10        |
|          | SPP/DEVB/SGSIT/OFFS/BV-01-C [Attribute ID Offset String GSIT – Service Name]     | 10        |
| 4.2.2    | Client Generic SDP Integrated Tests                                              | 11        |
|          | SPP/DEVA/CGSIT/SFC/BV-01-C [SDP Future Compatibility – IUT is SPP DevA]          | 11        |
| 4.3      | Application                                                                      | 12        |
| 4.3.1    | Establish Link and Set Up Virtual Serial Connection                              | 12        |
|          | SPP/DEVA/APP/BV-01-C [Initiate a serial cable emulation]                         | 12        |
| 4.3.2    | Accept Link and Virtual Serial Connection Establishment                          | 14        |
|          | SPP/DEVB/APP/BV-02-C [Accept initiation of a serial cable emulation]             | 14        |
| <b>5</b> | <b>Test case mapping</b>                                                         | <b>17</b> |
| <b>6</b> | <b>Revision history and acknowledgments</b>                                      | <b>18</b> |

# 1 Scope

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This Bluetooth document contains the Test Suite Structure (TSS) and test cases to test the implementation of the Bluetooth Serial Port Profile with the objective to provide a high probability of air interface interoperability between the tested implementation and other manufacturers' Bluetooth devices.

## 2 References, definitions, and abbreviations

---

### 2.1 References

This document incorporates provisions from other publications by dated or undated reference. These references are cited at the appropriate places in the text, and the publications are listed hereafter. Additional definitions and abbreviations can be found in [5] and [7].

- [1] Serial Port Profile, Version 1.1 or later
- [2] Bluetooth Core Specification: Generic Access Profile
- [3] Bluetooth Core Specification: Service Discovery Protocol
- [4] GAP Test Suite, GAP.TS
- [5] Bluetooth Core Specification, Version 2.0 or later
- [6] SDP Test Suite, SDP.TS
- [7] Test Strategy and Terminology Overview
- [8] ICS Proforma for Serial Port Profile
- [9] IXIT Proforma for Serial Port Profile
- [10] [Appropriate Language Mapping Tables](#) document

### 2.2 Definitions

In this Bluetooth document, the definitions from [1], [5], and [7] apply.

Certain terms that were identified as inappropriate have been replaced. For a list of the original terms and their replacement terms, see the Appropriate Language Mapping Tables document [10].

### 2.3 Acronyms and abbreviations

In this Bluetooth document, the definitions, acronyms, and abbreviations from [1], [5], and [7] apply.



## 3 Test Suite Structure (TSS)

### 3.1 Overview

The Serial Port Profile defines the protocols and procedures that are used by devices using Bluetooth for setting up a virtual serial cable emulation (like RS232) using RFCOMM between two peer devices.

The SPP depends on the GAP [2].

Figure 3.1 shows the protocol stack covered by SPP.

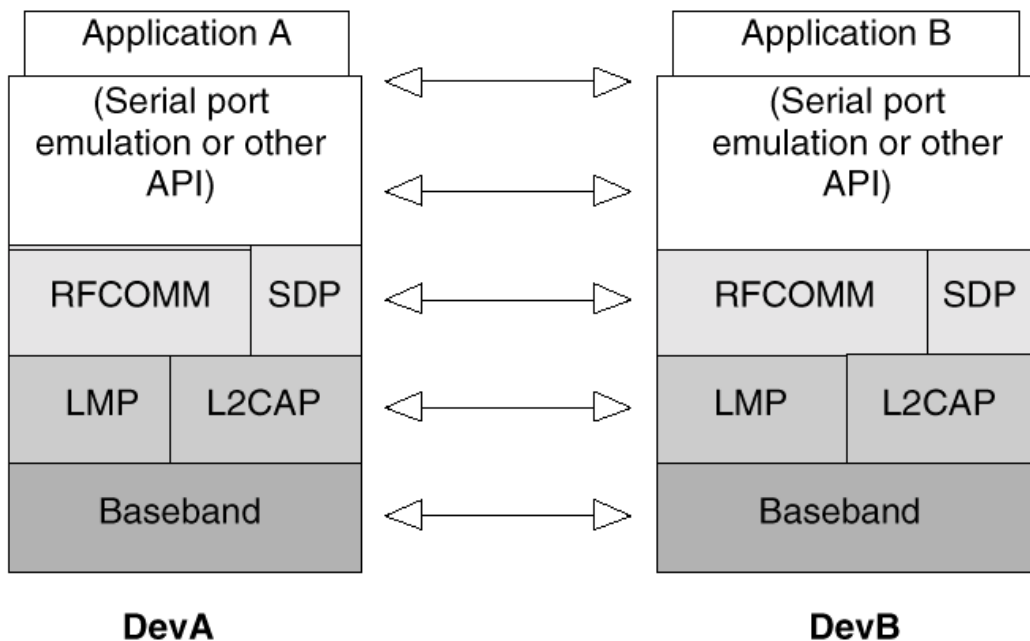


Figure 3.1: Protocol Stack for SPP

The Test Suite is broken into two sections: Generic SDP Integrated Tests and Application testing.

### 3.2 Test Strategy

The test objectives are to verify the functionality of the Serial Port Profile within a Bluetooth Host and enable interoperability between Bluetooth Hosts on different devices. The testing approach covers mandatory and optional requirements in the specification and matches these to the support of the IUT as described in the ICS. Any defined test herein is applicable to the IUT if the ICS logical expression defined in the Test Case Mapping Table (TCMT) evaluates to true.

The test equipment provides an implementation of the Radio Controller and the parts of the Host needed to perform the test cases defined in this Test Suite. A Lower Tester acts as the IUT's peer device and interacts with the IUT over-the-air interface. The configuration, including the IUT, needs to implement similar capabilities to communicate with the test equipment. For some test cases, it is necessary to stimulate the IUT from an Upper Tester. In practice, this could be implemented as a special test interface, a Man Machine Interface (MMI), or another interface supported by the IUT.

This Test Suite contains Valid Behavior (BV) tests complemented with Invalid Behavior (BI) tests where required. The test coverage mirrored in the Test Suite Structure is the result of a process that started with catalogued specification requirements that were logically grouped and assessed for testability enabling coverage in defined test purposes.

## 3.3 Test groups

### 3.3.1 Generic SDP Integrated Tests

The group demonstrates SDP interoperability by exercising the Generic SDP Integrated Tests defined in Section 6.3, Server test procedures (SGSIT), in [\[6\]](#).

### 3.3.2 Application

This group handles testing of application procedures. The test cases found in this group are based on the Serial Port Profile.

## 4 Test cases (TC)

### 4.1 Introduction

#### 4.1.1 Test case identification conventions

Test cases are assigned unique identifiers per the conventions in [7]. The convention used here is:

**<spec abbreviation>/<IUT role>/<class>/<feat>/<func>/<subfunc>/<cap>/<xx>-<nn>-<y>.**

Additionally, testing of this specification includes tests from the SDP Test Suite [6] referred to as Generic SDP Integrated Tests (GSIT); when used, the test cases in GSIT are referred to through a TCID string using the following convention:

**<spec abbreviation>/<IUT role>/<GSIT test group>/<GSIT class>/<xx>-<nn>-<y>.**

| Identifier Abbreviation | Spec Abbreviation <spec abbreviation>  |
|-------------------------|----------------------------------------|
| SPP                     | Serial Port Profile                    |
| Identifier Abbreviation | Role Identifier <IUT role>             |
| DEVA                    | Device A (Initiator) Role              |
| DEVB                    | Device B (Acceptor) Role               |
| Identifier Abbreviation | Reference Identifier <GSIT test group> |
| CGSIT                   | Client Generic SDP Integrated Tests    |
| SGSIT                   | Server Generic SDP Integrated Tests    |
| Identifier Abbreviation | Reference Identifier <GSIT class>      |
| ATTR                    | Attribute                              |
| OFFS                    | Attribute ID Offset String             |
| SERR                    | Service Record                         |
| SFC                     | SDP Future Compatibility               |
| Identifier Abbreviation | Feature Identifier <feat>              |
| APP                     | Application                            |

Table 4.1: SPP TC feature naming conventions

#### 4.1.2 Conformance

When conformance is claimed for a particular specification, all capabilities are to be supported in the specified manner. The mandated tests from this Test Suite depend on the capabilities to which conformance is claimed.

The Bluetooth Qualification Program may employ tests to verify implementation robustness. The level of implementation robustness that is verified varies from one specification to another and may be revised for cause based on interoperability issues found in the market.

Such tests may verify:

- That claimed capabilities may be used in any order and any number of repetitions not excluded by the specification
- That capabilities enabled by the implementations are sustained over durations expected by the use case
- That the implementation gracefully handles any quantity of data expected by the use case



- That in cases where more than one valid interpretation of the specification exists, the implementation complies with at least one interpretation and gracefully handles other interpretations
- That the implementation is immune to attempted security exploits

A single execution of each of the required tests is required to constitute a Pass verdict. However, it is noted that to provide a foundation for interoperability, it is necessary that a qualified implementation consistently and repeatedly pass any of the applicable tests.

In any case, where a member finds an issue with the test plan generated by the Bluetooth SIG qualification tool, with the test case as described in the Test Suite, or with the test system utilized, the member is required to notify the responsible party via an erratum request such that the issue may be addressed.

### 4.1.3 General Assumptions

No more than one ACL link exists between the Lower Tester and the IUT. Only one connection at a time and consequently only a point-to-point configuration is considered.

Support of one-slot packets is required to ensure data rates up to 128 kbps. The SPP is built upon the GAP, which means all tests defined in [4] have to be performed beforehand.

There are no fixed Central and Peripheral roles.

DevA and DevB can be either a Data Circuit Endpoint (DCE) or a Data Terminal Endpoint (DTE).

The role of DevA/DevB taken on by the IUT does not matter to achieve a pass verdict for some test cases for this Profile as indicated in the test purpose and is specified in the test case identifier for role agnostic tests as detailed in Table 4.1. The role of the IUT/Lower Tester for these tests is specified in the IXIT [9] in order to enable the correct test environment conditions to provoke the Lower Tester.

### 4.1.4 Pass/Fail verdict conventions

Each test case has an Expected Outcome section. The IUT is granted the Pass verdict when all the detailed pass criteria conditions within the Expected Outcome section are met.

The convention in this Test Suite is that, unless there is a specific set of fail conditions outlined in the test case, the IUT fails the test case as soon as one of the pass criteria conditions cannot be met. If this occurs, then the outcome of the test is a Fail verdict.

## 4.2 Generic SDP Integrated Tests

### 4.2.1 Server Generic SDP Integrated Tests

#### 4.2.1.1 Serial Port Profile – Device B

Execute the Generic SDP Integrated Tests defined in Section 6.3, Server test procedures (SGSIT), in [6] using Table 4.2 below as input:

| TCID                                                                                | Reference | Attribute ID Name              | Attribute ID definition source (Universal, Profile) | Value/ Secondary Value                                               | Attribute presence (Present/Present for [role], Optionally present, TCMT defined) |
|-------------------------------------------------------------------------------------|-----------|--------------------------------|-----------------------------------------------------|----------------------------------------------------------------------|-----------------------------------------------------------------------------------|
| SPP/DEVB/SGSIT/SERR/BV-01-C<br>[Service record GSIT – SPP DevB]                     | [1] 6.1   | ServiceClassIDList             | Universal                                           | “SerialPort” (UUID)                                                  | Present for DevB                                                                  |
| SPP/DEVB/SGSIT/ATTR/BV-01-C<br>[Attribute GSIT – Protocol Descriptor List]          | [1] 6.1   | ProtocolDescriptorList         | Universal                                           | “L2CAP” (UUID),<br>“RFCOMM” (UUID);<br>Server Channel – skip (Uint8) | Present for DevB                                                                  |
| SPP/DEVB/SGSIT/ATTR/BV-02-C<br>[Attribute GSIT – Bluetooth Profile Descriptor List] | [1] 6.1   | BluetoothProfileDescriptorList | Universal                                           | “SerialPort” (UUID);<br>Version – “0x0102”                           | TCMT defined                                                                      |

Table 4.2: Input for the Serial Port Profile Device B SGSIT SDP test procedure

#### 4.2.1.2 Serial Port Profile – Attribute ID Offset String tests

Execute the Generic SDP Integrated Tests defined in Section 6.3, Server test procedures (SGSIT), in [6] using Table 4.3 below as input:

| TCID                                                                            | Reference | ServiceSearchPattern | Attribute ID name | Attribute ID Offset | Attribute presence (Present/Present for [role], Optionally present, TCMT defined) |
|---------------------------------------------------------------------------------|-----------|----------------------|-------------------|---------------------|-----------------------------------------------------------------------------------|
| SPP/DEVB/SGSIT/OFFS/BV-01-C<br>[Attribute ID Offset String GSIT – Service Name] | [1] 6.1   | SerialPort           | ServiceName       | 0x0000              | TCMT defined                                                                      |

Table 4.3: Input for the Serial Port Profile SGSIT Attribute ID Offset String tests



### 4.2.2 Client Generic SDP Integrated Tests

Execute the Generic SDP Future Compatibility Tests defined in Section 6.4, Client test procedures (CGSIT), in [6] using Table 4.4 below as input:

| TCID                                                                                       | Reference                 | Service Record Service Class UUID description | Lower Tester SDP record initial conditions                                                                                                                  |
|--------------------------------------------------------------------------------------------|---------------------------|-----------------------------------------------|-------------------------------------------------------------------------------------------------------------------------------------------------------------|
| <a href="#">SPP/DEVA/CGSIT/SFC/BV-01-C</a><br>[SDP Future Compatibility – IUT is SPP DevA] | <a href="#">[1]</a> 3.1.1 | SerialPort                                    | The Lower Tester exposes an SPP DevB SDP record.<br>The version in the Bluetooth Profile Descriptor List is greater than the most recently adopted version. |

Table 4.4: Input for the Client CGSIT SDP future compatibility tests

## 4.3 Application

Test group objectives:

- To verify the correct implementation of the Application services.
- The A-party of GAP is equivalent to DevA and the B-party is equivalent to DevB.
- There are no fixed Central and Peripheral roles.

### 4.3.1 Establish Link and Set Up Virtual Serial Connection

Test subgroup objectives:

- Verify the correct handling of setting up a virtual serial connection in the Bluetooth Serial Port Profile.

#### SPP/DEVA/APP/BV-01-C [Initiate a serial cable emulation]

- Test Purpose

Verify that the IUT establishes a connection to an emulated serial port in the Lower Tester. The IUT is a device taking on the role as DevA. The Lower Tester is Acceptor and DevB.

- Reference

[\[1\]](#) 3.1.1

- Initial Condition

- An ACL link is set up between the IUT and the Lower Tester.
- The Lower Tester is the SDP server and has all its services placed in the root browse group. The root browse group contains the service record for SerialPortProfile with the ServiceName "COM5". The BrowseGroupList attribute is therefore embedded in the Lower Tester's service record.

- Test Procedure

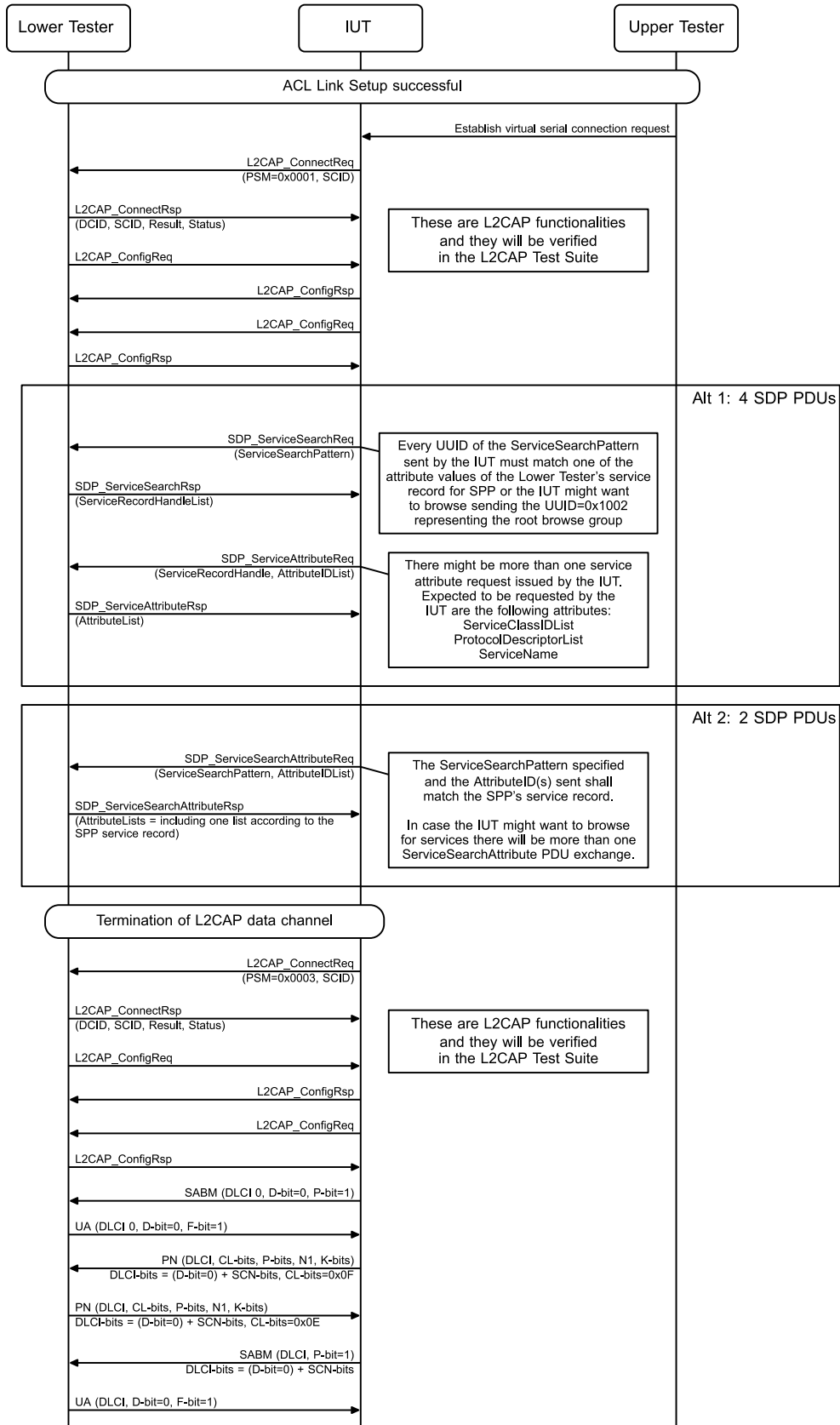


Figure 4.1: SPP/DEVA/APP/BV-01-C [Initiate a serial cable emulation]

1. The IUT requests an L2CAP channel to the Lower Tester's SDP server database.
  2. The IUT submits a query using SDP to find out the RFCOMM Server Channel number. The IUT may browse the Lower Tester's SDP services.
  3. The IUT requests a new L2CAP channel to the Lower Tester's RFCOMM entity.
  4. The IUT initiates an RFCOMM session.
  5. The IUT initiates parameter negotiation before starting a new data link connection.
  6. The IUT starts a new data link connection on the RFCOMM session using the server channel number.
- Test Condition
 

There must be an indication to the MMI in case a virtual serial connection is ready to be used for communication.

The value of K bits indicates the initial credits issued by the IUT and should be taken from the IXIT [9].
  - Expected Outcome
 

Pass verdict

The IUT submits a query using SDP.

And the IUT transmits an SABM command to initiate an RFCOMM session.

And the IUT transmits a PN command to negotiate DLC parameters with CL-bits set to 0x0F and I-bits, T-bits and NA-bits all set to zero.

And the IUT transmits a SABM command to start a new data link connection. K bits indicate the initial credits issued by the IUT.
  - Notes
 

Upon the SDP PDU are exchanged the IUT could terminate the existing L2CAP data channel and an L2CA\_DisconnectInd event arises at the Lower Tester. In that case the Lower Tester has to reply with a disconnect response. If the IUT requests encryption, the Lower Tester accepts.

The IUT should initiate the baseband link unless already established.

#### 4.3.2 Accept Link and Virtual Serial Connection Establishment

Test subgroup objectives:

- Verify the correct handling of setting up a virtual serial connection in the Bluetooth Serial Port Profile.

#### SPP/DEVB/APP/BV-02-C [Accept initiation of a serial cable emulation]

- Test Purpose
 

Verify that the IUT accepts a connection request from the Lower Tester to its emulated serial port. The IUT is a device taking on the role as DevB. The Lower Tester is Initiator.
- Reference
 

[1] 3.1.2, 3.1.3
- Initial Condition
  - An ACL link is set up between the IUT and the Lower Tester.



- Test Procedure

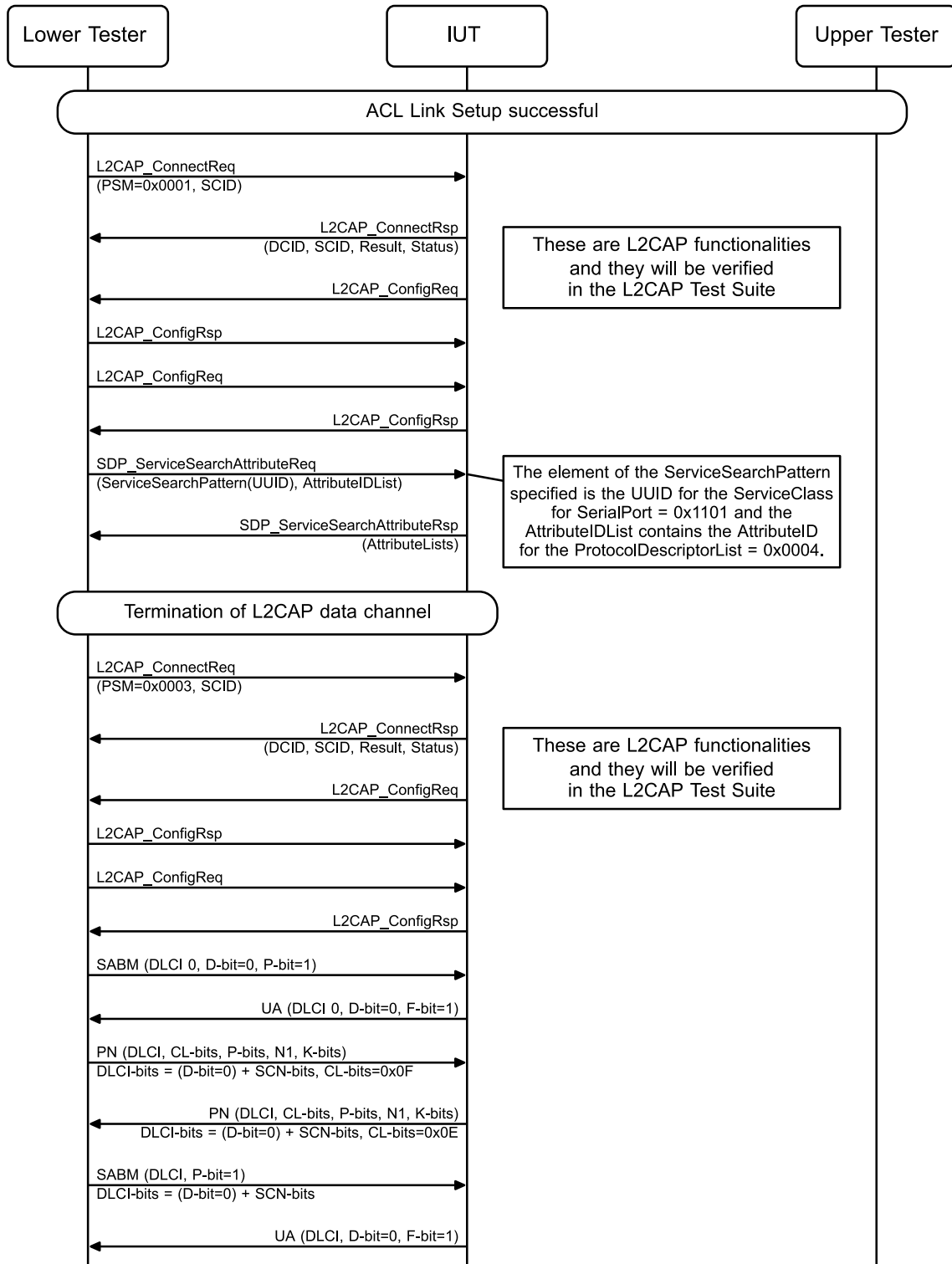


Figure 4.2: SPP/DEVB/APP/BV-02-C [Accept initiation of a serial cable emulation]

1. The Lower Tester requests an L2CAP channel to the IUT's SDP server database.
2. The Lower Tester submits a query to the IUT using SDP to find the SPP service record with the associated RFCOMM Server Channel number.
3. The Lower Tester requests a new L2CAP channel to the IUT's RFCOMM entity.

4. The Lower Tester initiates an RFCOMM session.
5. The Lower Tester initiates parameter negotiation before starting a new data link connection.
6. The Lower Tester starts a new data link connection on the RFCOMM session using the server channel number.

- Test Condition

The value of K bits indicates the initial credits issued by the IUT and should be taken from the IXIT [\[9\]](#).

- Expected Outcome

Pass verdict

The IUT responds to a query from the Lower Tester using SDP.

And the IUT transmits a UA response to initiate an RFCOMM session.

And the IUT transmits a PN response to negotiate DLC parameters with CL-bits set to 0x0E and I-bits, T-bits and NA-bits all set to zero.

And the IUT transmits a UA response to start a new data link connection. K bits indicate the initial credits issued by the IUT.

- Notes

Upon the SDP PDU are exchanged the IUT could terminate the existing L2CAP data channel and an L2CAP\_DisconnectInd event arises at the Lower Tester. In that case the Lower Tester has to reply with a disconnect response. If the IUT requests encryption, the Lower Tester accepts.

The Lower Tester should initiate the baseband link unless already established.



## 5 Test case mapping

The Test Case Mapping Table (TCMT) maps test cases to specific requirements in the ICS. The IUT is tested in all roles for which support is declared in the ICS document.

The columns for the TCMT are defined as follows:

**Item:** Contains a logical expression based on specific entries from the associated ICS document. Contains a logical expression (using the operators AND, OR, NOT as needed) based on specific entries from the applicable ICS document(s). The entries are in the form of y/x references, where y corresponds to the table number and x corresponds to the feature number as defined in the ICS document for Serial Port profile (SPP) [8].

**Feature:** A brief, informal description of the feature being tested.

**Test Case(s):** The applicable test case identifiers are required for Bluetooth Qualification if the corresponding y/x references defined in the Item column are supported. Further details about the function of the TCMT are elaborated in [7].

For the purpose and structure of the ICS/IXIT, refer to [7].

| Item                                               | Feature                                          | Test Case(s)                                               |
|----------------------------------------------------|--------------------------------------------------|------------------------------------------------------------|
| SPP 2/1b                                           | SPP Device B SDP Service                         | SPP/DEVB/SGSIT/SERR/BV-01-C<br>SPP/DEVB/SGSIT/ATTR/BV-01-C |
| SPP 0/2 AND SPP 2/1b                               | SPP Device B SDP Service,<br>SPP 1.2             | SPP/DEVB/SGSIT/ATTR/BV-02-C                                |
| SPP 4/5                                            | SPP Device B SDP attribute:<br>Service Name      | SPP/DEVB/SGSIT/OFFS/BV-01-C                                |
| SPP 1/1 AND SPP 2/1<br>AND SPP 2/1a AND<br>SPP 3/1 | Initiate a serial cable emulation                | SPP/DEVA/APP/BV-01-C<br>SPP/DEVA/CGSIT/SFC/BV-01-C         |
| SPP 1/2 AND SPP 2/1<br>AND SPP 2/1b AND<br>SPP 3/2 | Accept initiation of a serial cable<br>emulation | SPP/DEVB/APP/BV-02-C                                       |

Table 5.1: Test case mapping

## 6 Revision history and acknowledgments

### Revision History

| Publication Number | Revision Number | Date                      | Comments                                                                                                                                                           |
|--------------------|-----------------|---------------------------|--------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| 0                  | 1.1.1           | 03-21-2005                | Corrected document revision number.                                                                                                                                |
|                    | 1.1.2r0         | 2006-11-22                | Editorial adjustments.                                                                                                                                             |
|                    | 1.1.2r1         | 2006-12-03                | Input Reviewer's comments<br>Formatting: Moved MSCs into test case section<br>Moved Uncertainties into Notes section<br>(Spell checked, updated TOC )              |
|                    | 1.1.2r2         | 2006-12-20                | Included TSE 2007<br>Added section 5.1.4 Conformance                                                                                                               |
| 1                  | 1.1.2           | 2007-01-08                | Prepare for publication.                                                                                                                                           |
|                    | 1.1.3r0         | 2008-02                   | TSE 2384: SPP/DEVB/APP/BV-02-C,<br>SPP/NA/APP/BV-03-C (legacy test case IDs<br>TP/APP/BV-02-C, TP/APP/BV-03-C): Correct MSCs                                       |
| 2                  | 1.1.3           | 2008-04                   | Prepare for publication.                                                                                                                                           |
| 3                  | 1.2.0           | 2012-06-14<br>2012-07-24  | Update versioning to accommodate SPP_SPEC_v1.2;<br>updated conformance section; prepared for<br>publication.                                                       |
|                    | 1.2.1r01        | 2013-09-30                | TSE 5292: Removed SDP test cases (TP/SDP/BV-01-C, TP/SDP/BV-02-C, TP/SDP/BV-03-C), updated TCMT.                                                                   |
|                    | 1.2.1r03        | 2013-11-13                | Updated Copyright Information<br>BQRB Review: Removed references to SDP Sections                                                                                   |
| 4                  | 1.2.1           | 2013-12-03                | Prepare for Publication                                                                                                                                            |
|                    | 1.2.2r00        | 2016-08-29                | Converted to new Test Case ID conventions as<br>defined in TSTO v4.1.                                                                                              |
|                    | 1.2.2r01        | 2016-11-03                | Converted to current template.                                                                                                                                     |
|                    | 1.2.2r02        | 2016-11-08                | TSE 8096: following the deprecation of the PARK<br>feature: remove TP/APP/BV-04-C in its entirety and<br>update test case note applicable to TP/APP/BV-06-C        |
| 5                  | 1.2.2           | 2016-12-13                | Approved by BTI. Prepared for TCRL 2016-2<br>publication.                                                                                                          |
|                    | 1.2.3r00        | 2018-03-13                | TSE 10406 (rating 4): Deleted SPP/DEVA-<br>DEVB/APP/BV-03-C, SPP/DEVA-DEVB/APP/BV-05-<br>C, and SPP/DEVA-DEVB/APP/BV-06-C and their<br>corresponding TCMT entries. |
| 6                  | 1.2.3           | 2018-07-01                | Approved by BTI. Prepared for TCRL 2018-1<br>publication.                                                                                                          |
|                    | 1.2.4r00-r01    | 2019-04-15–<br>2019-05-31 | TSE 11676 (rating 2): Revised TCMT for newly added<br>ICS 2/1a and 2/1b for test cases SPP/DEVA/APP/BV-<br>01-C and SPP/DEVB/APP/BV-02-C.                          |
| 7                  | 1.2.4           | 2019-07-28                | Approved by BTI. Prepared for TCRL 2019-1<br>publication.                                                                                                          |

| Publication Number | Revision Number | Date                    | Comments                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                       |
|--------------------|-----------------|-------------------------|--------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
|                    | p8r00–r02       | 2024-01-08 – 2024-04-23 | <p>TSE 24536 (rating 4): Added a new GSIT section with new TCs SPP/DEVB/SGSIT/SEERR/BV-01-C, SPP/DEVB/SGSIT/ATTR/BV-01-C and -02-C, SPP/DEVB/SGSIT/OFFS/BV-01-C, and SPP/DEVA/CGSIT/SFC/BV-01-C. Updated the TCMT accordingly. Updated the TC class naming conventions table.</p> <p>TSE 24744 (rating 1): Performed editorial work to align with the current TS template, including updates to the title page, scope, references, Test Suite Structure, TCID conventions, conformance, Pass/Fail verdict conventions, TCMT introduction, and acknowledgments. Converted single-TC section headings from Heading 4 to Heading 8. Added a Publication Number column to the revision history and revised the document numbering convention, setting the last released publication of 1.2.4 as p7. Deleted draft revision history comments prior to p0.</p> <p>Replaced Bluetooth logo in footer and updated the copyright page to align with the latest version of the DNMD.</p> |
| 8                  | p8              | 2024-07-01              | Approved by BTI on 2024-05-22. Prepared for TCRL 2024-1 publication.                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                                           |

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